Notice of References Cited Application/Control No. 10/567,037 Applicant(s)/Patent Under Reexamination VAN DE SLUIS ET AL. Examiner ZIAUL CHOWDHURY 2192 Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,561,799 A	10-1996	Khalidi et al.	707/200
*	В	US-5,598,524 A	01-1997	Johnston et al.	715/769
*	С	US-5,644,738 A	07-1997	Goldman et al.	715/825
*	D	US-5,838,322 A	11-1998	Nakajima et al.	715/846
*	Е	US-6,008,806 A	12-1999	Nakajima et al.	715/744
*	F	US-6,177,905 B1	01-2001	Welch, Bryan J.	342/357.13
*	G	US-2001/0019338 A1	09-2001	Roth, Steven William	345/811
*	Ι	US-2001/0029184 A1	10-2001	l'Anson et al.	455/456
*	I	US-2002/0122055 A1	09-2002	Parupudi et al.	345/737
*	J	US-6,678,724 B2	01-2004	Nakajima et al.	709/219
*	K	US-7,089,502 B2	08-2006	Nakajima et al.	715/777
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.